

Search Notes

Application/Control No.

09/754,376

Examiner

Matthew Heneghan

Applicant(s)/Patent under
Reexamination

YOSHIHIRO, TAKUJI

Art Unit

2134

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
keyword search for 3D imaging using lasers/needles, see notes	2/23/2006	MH